



PATENT APPLICATION

IN THE U.S. PATENT AND TRADEMARK OFFICE

March 29, 2005

Applicant(s) : X. Shawn YU et al.

For : PANEL ARRANGEMENT

Serial No. : 10/730 617 Group: 3673

Confirmation No.: 4027

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Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

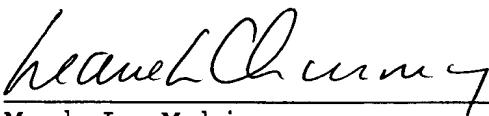
INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(b) (4) and 1.98, enclosed herewith is Form PTO-1449 and the references cited thereon. Copies of cited U.S. references are not submitted in accordance with 37 CFR 1.98(a).

Further consideration is respectfully solicited.

Respectfully submitted,


MLM/mag

Mark L. Maki

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Encl: Form PTO-1449

INFORMATION DISCLOSURE CITATION	Applicant: X. Shawn YU et al. Ser.No. : 10/730 617 Filed : December 8, 2003 Conf. No.: 4027 Atty.Ref.: Haworth C-205D Group : 3673
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MAR 29 2005

Examiner Initials	Document Number	Date	Name	U.S. PATENT DOCUMENTS		Filing Date
				Class	Sub Class	
	AA	4 433 630	02/1984	Laborie		
	AB	5 301 477	4/1994	Rellinger et al.		
	AC	6 021 613	2/2000	Reuter et al.		
	AD	6 167 664	1/2001	Reuter et al.		
	AE	6 367 213	4/2002	Reuter et al.		
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Translation	
				Sub Class	Yes
AL					
AM					
AN					
AO					
AP					

OTHER DOCUMENTS (Including Author, Title, Date, Pages, Etc.)

AR	
AS	

EXAMINER DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.